

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/940,174 | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | Examiner EVENS J. AUGUSTIN | Art Unit 3621 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| * | A | US-6,519,700 B1 | 02-2003 | Ram et al. | 713/193 |
| * | B | US-6,782,190 B1 | 08-2004 | Morito, Hajime | 386/94 |
| * | C | US-6,748,539 | 06-2004 | Lotspiech, Jeffrey Bruce | 726/20 |
| * | D | US-6,028,936 | 02-2000 | Hillis, W. Daniel | 713/168 |
| * | E | US-6,584,160 | 06-2003 | Amrany et al. | 375/296 |
| * | F | US-5,857,021 | 01-1999 | Kataoka et al. | 705/54 |
| * | G | US-6,367,010 | 04-2002 | Venkatram et al. | 713/171 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.